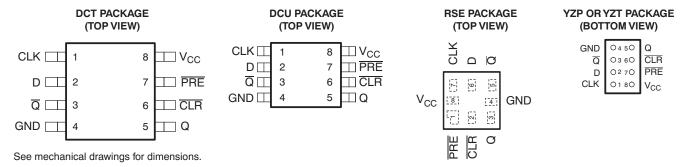
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#### **FEATURES**

- Available in the Texas Instruments
   NanoFree<sup>™</sup> Package
- Optimized for 1.8-V Operation and Is 3.6-V I/O Tolerant to Support Mixed-Mode Signal Operation
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Sub-1-V Operable
- Max t<sub>pd</sub> of 1.5 ns at 1.8 V

- Low Power Consumption, 10-μA Max I<sub>CC</sub>
- ±8-mA Output Drive at 1.8 V
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)



#### **DESCRIPTION/ORDERING INFORMATION**

This single positive-edge-triggered D-type flip-flop is operational at 0.8-V to 2.7-V  $V_{CC}$ , but is designed specifically for 1.65-V to 1.95-V  $V_{CC}$  operation.

A low level at the preset (PRE) or clear (CLR) input sets or resets the outputs, regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not related directly to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs. To better optimize the flip-flop for higher frequencies, the CLR input overrides the PRE input when they are both low.

NanoFree<sup>™</sup> package technology is a major breakthrough in IC packaging concepts, using the die as the package.

This device is fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

NanoFree is a trademark of Texas Instruments.



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#### ORDERING INFORMATION

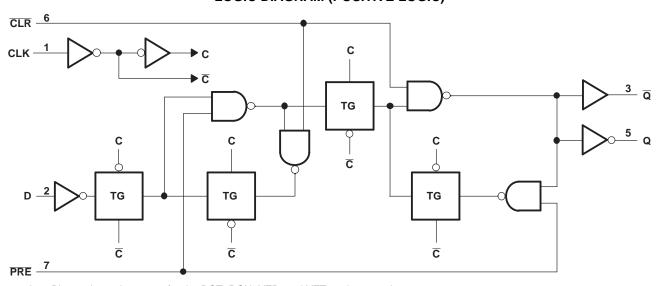
T <sub>A</sub>	PACKAGE <sup>(1)(2)</sup>		ORDERABLE PART NUMBER	TOP-SIDE MARKING(3)
-40°C to 85°C	NanoFree <sup>™</sup> – WCSP (DSBGA) 0.23-mm Large Bump – YZP (Pb-free)	Reel of 3000	SN74AUC1G74YZPR	UP
	NanoFree <sup>™</sup> – WCSP (DSBGA) 0.23-mm Large Bump – YZT (Pb-free)	Reel of 3000	SN74AUC1G74YZTR	01 _
	QFN - RSE	Reel of 3000	SN74AUC1G74RSER	UP
	SSOP - DCT	Reel of 3000	SN74AUC1G74DCTR	U74
	VSSOP - DCU	Reel of 3000	SN74AUC1G74DCUR	U74_

- (1) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.
- For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
- DCT: The actual top-side marking has three additional characters that designate the year, month, and assembly/test site. DCU: The actual top-side marking has one additional character that designates the assembly/test site. YZP/YZT: The actual top-side marking has three preceding characters to denote year, month, and sequence code, and one following character to designate the assembly/test site. Pin 1 identifier indicates solder-bump composition (1 = SnPb, • = Pb-free).

#### **FUNCTION TABLE**

	INP	UTS		OUTPUTS				
PRE	CLR	CLK	D	Q	Q			
L	Н	Χ	Χ	Н	L			
X	L	Χ	X	L	Н			
Н	Н	$\uparrow$	Н	Н	L			
Н	Н	$\uparrow$	L	L	Н			
Н	Н	L	Χ	$Q_0$	$\overline{Q}_{0}$			

## LOGIC DIAGRAM (POSITIVE LOGIC)



Pin numbers shown are for the DCT, DCU, YZP, and YZT packages only.

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## Absolute Maximum Ratings<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT	
$V_{CC}$	Supply voltage range		-0.5	3.6	V	
VI	Input voltage range (2)		-0.5	3.6	V	
Vo	Voltage range applied to any output in the	ne high-impedance or power-off state (2)	-0.5	3.6	V	
Vo	Output voltage range <sup>(2)</sup>		-0.5	V <sub>CC</sub> + 0.5	V	
$I_{IK}$	Input clamp current	V <sub>I</sub> < 0		-50	mA	
$I_{OK}$	Output clamp current		-50	mA		
Io	Continuous output current			±20	mA	
	Continuous current through V <sub>CC</sub> or GND			±100	mA	
		DCT package		220		
Δ	Package thermal impedance (3)	DCU package		227	°C/W	
$\theta_{JA}$	Fackage thermal impedance (*)	RSE package		253		
		YZP/YZT package		102		
T <sub>stg</sub>	Storage temperature range		-65	150	°C	

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## Recommended Operating Conditions<sup>(1)</sup>

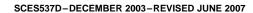
			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		0.8	2.7	V
		V <sub>CC</sub> = 0.8 V	V <sub>CC</sub>		
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 1.1 V to 1.95 V	$0.65 \times V_{CC}$		V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		
		V <sub>CC</sub> = 0.8 V		0	
$V_{IL}$	Low-level input voltage	$V_{CC} = 1.1 \text{ V to } 1.95 \text{ V}$		$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	
V <sub>I</sub>	Input voltage		0	3.6	V
Vo	Output voltage		0	V <sub>CC</sub>	V
		V <sub>CC</sub> = 0.8 V		-0.7	
		V <sub>CC</sub> = 1.1 V		-ვ	
$I_{OH}$	High-level output current	V <sub>CC</sub> = 1.4 V		-5	mA
		V <sub>CC</sub> = 1.65 V		-8	
		V <sub>CC</sub> = 2.3 V		6	
		V <sub>CC</sub> = 0.8 V		0.7	
		V <sub>CC</sub> = 1.1 V		3	
$I_{OL}$	Low-level output current	V <sub>CC</sub> = 1.4 V		5	mA
		V <sub>CC</sub> = 1.65 V		8	
		V <sub>CC</sub> = 2.3 V		9	
		$V_{CC} = 0.8 \text{ V to } 1.65 \text{ V}^{(2)}$		20	
$\Delta t/\Delta v$	Input transition rise or fall rate	$V_{CC} = 1.65 \text{ V to } 2.3 \text{ V}^{(3)}$		20	
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}^{(3)}$		20	
T <sub>A</sub>	Operating free-air temperature		-40	85	°C

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(3)</sup> The package thermal impedance is calculated in accordance with JESD 51-7.

<sup>(2)</sup> The data was taken at  $C_L = 15$  pF,  $R_L = 2$  k $\Omega$  (see Figure 1). (3) The data was taken at  $C_L = 30$  pF,  $R_L = 500$   $\Omega$  (see Figure 1).





#### **Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN TYP <sup>(1)</sup> MA	X UNIT
	$I_{OH} = -100 \mu A$	0.8 V to 2.7 V	V <sub>CC</sub> - 0.1	
	$I_{OH} = -0.7 \text{ mA}$	0.8 V	0.55	
Vall	$I_{OH} = -3 \text{ mA}$	1.1 V	0.8	V
V <sub>OH</sub>	$I_{OH} = -5 \text{ mA}$	1.4 V	1	V
	$I_{OH} = -8 \text{ mA}$	1.65 V	1.2	
	$I_{OH} = -9 \text{ mA}$	2.3 V	1.8	
	I <sub>OL</sub> = 100 μA	0.8 V to 2.7 V	0	2
	I <sub>OL</sub> = 0.7 mA	0.8 V	0.25	
V	I <sub>OL</sub> = 3 mA	1.1 V	0	3 V
V <sub>OL</sub>	I <sub>OL</sub> = 5 mA	1.4 V	0	4
	I <sub>OL</sub> = 8 mA	1.65 V	0.4	5
	I <sub>OL</sub> = 9 mA	2.3 V	0	6
I <sub>I</sub> All inputs	$V_I = V_{CC}$ or GND	0 to 2.7 V		5 μΑ
I <sub>off</sub>	$V_I$ or $V_O = 2.7 \text{ V}$	0	±1	0 μΑ
I <sub>CC</sub>	$V_I = V_{CC}$ or GND, $I_O = 0$	0.8 V to 2.7 V	1	0 μΑ
C <sub>I</sub>	$V_I = V_{CC}$ or GND	2.5 V	2.5	pF

<sup>(1)</sup> All typical values are at  $T_A = 25$ °C.

## **Timing Requirements**

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			V <sub>CC</sub> = 0.8 V		V <sub>CC</sub> = 1.2 V ± 0.1 V		V <sub>CC</sub> = 1.5 V ± 0.1 V		1.8 V 15 V	V <sub>CC</sub> = 2.5 V ± 0.2 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>clock</sub>	Clock frequency		50		200		225		250		275	MHz
t <sub>w</sub> Pulse		CLK	2	1		1		1		1		
	Pulse duration	PRE or CLR low	5	1.5		1		1		1		ns
		Data	2.2	0.6		0.5		0.5		0.4		
t <sub>su</sub>	Setup time before CLK↑	PRE or CLR inactive	2.9	1.6		0.9		0.7		0.4		ns
t <sub>h</sub>	Hold time, data after CLK↑		1.2	0.5		0.4		0.3		0.3		ns

## **Switching Characteristics**

over recommended operating free-air temperature range,  $C_L = 15 \text{ pF}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 0.8 V	V <sub>CC</sub> = 1.2 V ± 0.1 V		V <sub>CC</sub> = 1.5 V ± 0.1 V		V <sub>CC</sub> = 1.8 V ± 0.15 V			V <sub>CC</sub> = 2.5 V ± 0.2 V		UNIT	
	(INPOT)	(001701)	TYP	MIN	MAX	MIN	MAX	MIN	TYP	MAX	MIN	MAX		
f <sub>max</sub>			50	200		225		250			275		MHz	
t <sub>pd</sub>	CLK	Q	10.3	1.7	3.7	1.2	2.5	1	1.2	1.7	0.8	1.2		
		Q	9.6	1	3.8	1	3	0.9	1.1	1.5	0.7	1.1	ns	
	PRE or CLR	Q or $\overline{\mathbb{Q}}$	12.9	2	4.5	0.9	3.1	1.1	1.5	2.2	0.9	1.5		



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## **Switching Characteristics**

over recommended operating free-air temperature range,  $C_L = 30 \text{ pF}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)		c = 1.8 0.15 \		V <sub>CC</sub> = ± 0.	UNIT	
	(INPUT)	(001701)	MIN	TYP	MAX	MIN	MAX	,
f <sub>max</sub>			250			275		ns
	CLK	Q	1.5	1.9	2.4	1.4	1.8	
$t_{pd}$	CLK	IQ	1.4	1.9	2.4	1.3	1.8	ns
·	PRE or CLR	Q or $\overline{Q}$	1.7	2.2	2.8	1.5	2.1	

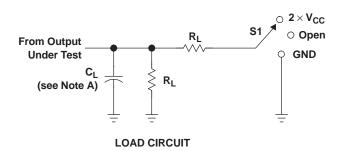
## **Operating Characteristics**

 $T_A = 25^{\circ}C$ 

	PARAMETER	TEST CONDITIONS	V <sub>CC</sub> = 0.8 V TYP	V <sub>CC</sub> = 1.2 V TYP	V <sub>CC</sub> = 1.5 V TYP	V <sub>CC</sub> = 1.8 V TYP	V <sub>CC</sub> = 2.5 V TYP	UNIT
$C_{pd}$	Power dissipation capacitance	f = 10 MHz	35	36	39	44	59	pF

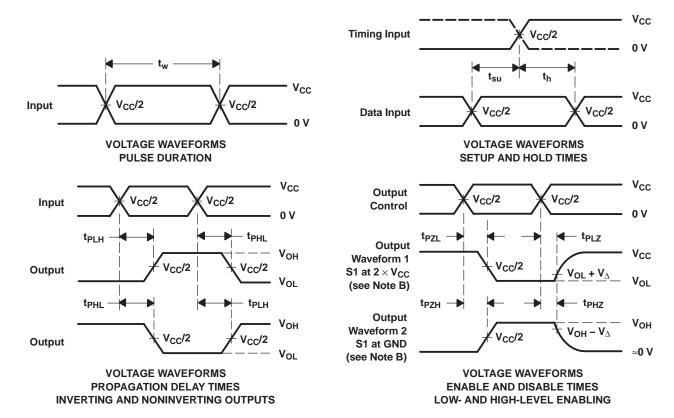


#### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	$2 \times V_{CC}$
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

V <sub>CC</sub>	CL	R <sub>L</sub>	$oldsymbol{V}_\Delta$
0.8 V	15 pF	<b>2 k</b> Ω	0.1 V
1.2 V $\pm$ 0.1 V	15 pF	<b>2 k</b> Ω	0.1 V
1.5 V $\pm$ 0.1 V	15 pF	<b>2 k</b> Ω	0.1 V
1.8 V ± 0.15 V	15 pF	<b>2 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	15 pF	<b>2 k</b> Ω	0.15 V
1.8 V $\pm$ 0.15 V	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	30 pF	500 Ω	0.15 V



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , slew rate  $\geq$  1 V/ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G. t<sub>PLH</sub> and t<sub>PHL</sub> are the same as t<sub>pd</sub>.
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms





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#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
SN74AUC1G74DCTR	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	U74 Z	Samples
SN74AUC1G74DCTRE4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	U74 Z	Samples
SN74AUC1G74DCTRG4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	U74 Z	Samples
SN74AUC1G74DCUR	ACTIVE	US8	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 85	(74 ~ U74R) UZ	Samples
SN74AUC1G74DCURE4	ACTIVE	US8	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	U74R	Samples
SN74AUC1G74DCURG4	ACTIVE	US8	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	U74R	Samples
SN74AUC1G74RSER	ACTIVE	UQFN	RSE	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	UP	Samples
SN74AUC1G74RSERG4	ACTIVE	UQFN	RSE	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	UP	Samples
SN74AUC1G74YZPR	ACTIVE	DSBGA	YZP	8	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	(UP7 ~ UPN)	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.



## PACKAGE OPTION ADDENDUM

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- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

## **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AUC1G74DCUR	US8	DCU	8	3000	180.0	9.0	2.05	3.3	1.0	4.0	8.0	Q3
SN74AUC1G74DCUR	US8	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74AUC1G74DCURG4	US8	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74AUC1G74RSER	UQFN	RSE	8	3000	179.0	8.4	1.7	1.7	0.76	4.0	8.0	Q2
SN74AUC1G74YZPR	DSBGA	YZP	8	3000	178.0	9.2	1.02	2.02	0.63	4.0	8.0	Q1

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\*All dimensions are nominal

All differentiations are normal										
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)			
SN74AUC1G74DCUR	US8	DCU	8	3000	182.0	182.0	20.0			
SN74AUC1G74DCUR	US8	DCU	8	3000	202.0	201.0	28.0			
SN74AUC1G74DCURG4	US8	DCU	8	3000	202.0	201.0	28.0			
SN74AUC1G74RSER	UQFN	RSE	8	3000	203.0	203.0	35.0			
SN74AUC1G74YZPR	DSBGA	YZP	8	3000	220.0	220.0	35.0			

## DCT (R-PDSO-G8)

#### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion
- D. Falls within JEDEC MO-187 variation DA.

## DCT (R-PDSO-G8)

## PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# DCU (R-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



NOTES:

- A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
  - D. Falls within JEDEC MO-187 variation CA.



DCU (S-PDSO-G8)

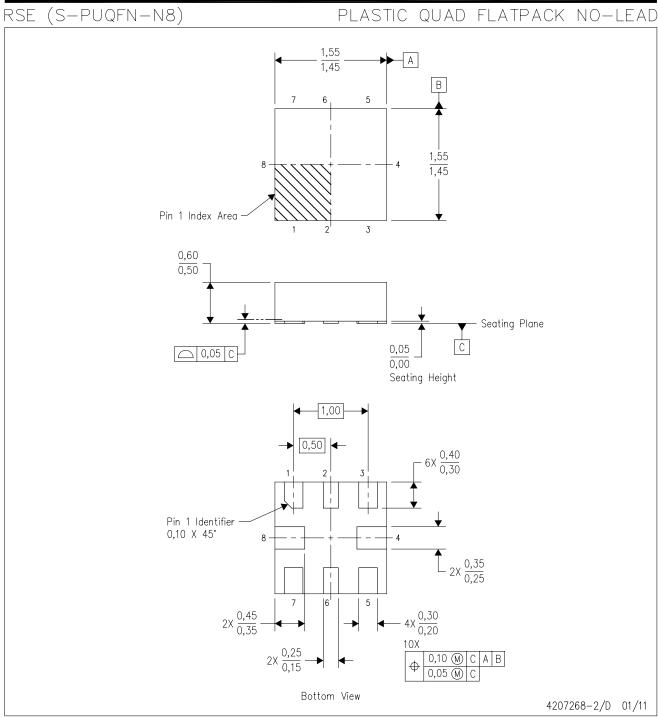
PLASTIC SMALL OUTLINE PACKAGE (DIE DOWN)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





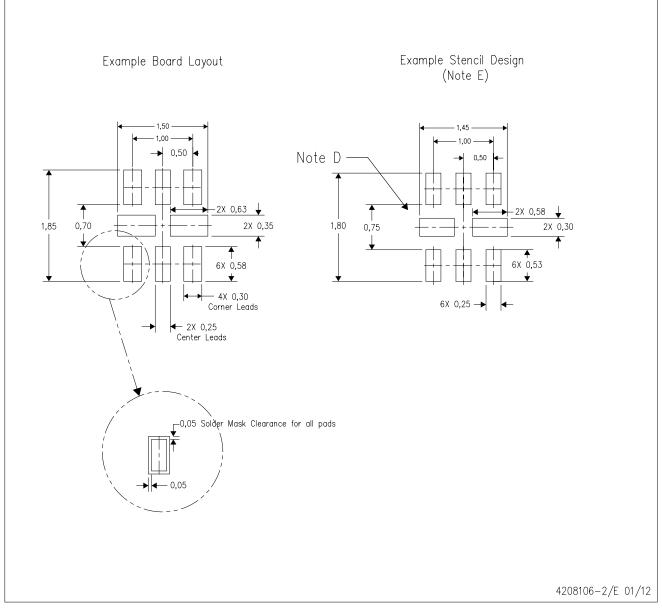
NOTES: All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
  C. QFN (Quad Flatpack No-Lead) package configuration.
  D. This package complies to JEDEC MO-288 variation UECD.



## RSE (S-PUQFN-N8)

### PLASTIC QUAD FLATPACK NO-LEAD

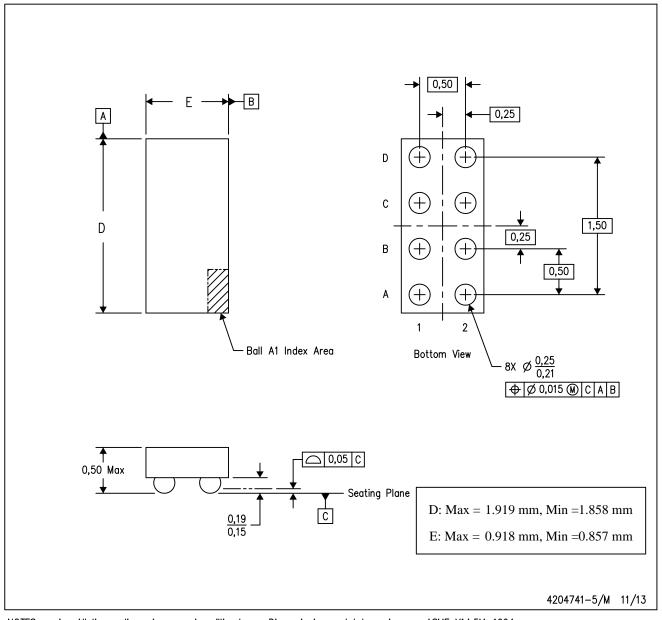


- NOTES: A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Publication IPC-7351 is recommended for alternate designs.
  - D. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.
  - E. Maximum stencil thickness 0,127 mm (5 mils). All linear dimensions are in millimeters.
  - F. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
  - G. Side aperture dimensions over-print land for acceptable area ratio > 0.66. Customer may reduce side aperture dimensions if stencil manufacturing process allows for sufficient release at smaller opening.



YZP (R-XBGA-N8)

DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.

- B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.

NanoFree is a trademark of Texas Instruments.



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